

# **FDS7064SN3**

# 30V N-Channel PowerTrench® SyncFET™

### **General Description**

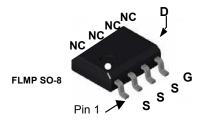
The FDS7064SN3 is designed to improve the efficiency of Buck Regulators. Used as the Synchronous rectifier, (Low side MOSFET), losses can be reduced, not only in this device, but also in the Control switch, (High side MOSFET). After the low side MOSFET turns off, reverse recovery current in the body diode is dissipated in the High Side device. A Discrete Schottky diode in parallel with the Low Side MOSFET can lower the reverse recovery current, but parasitic PCB and Package Inductance reduce the effectiveness of the Schottky. SyncFET<sup>TM</sup> technology reduces this inductance to a minimum by providing a monolithic solution (MOSFET and Schottky in the same die), resulting in optimum performance.

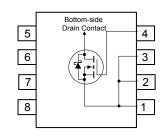
### **Applications**

• Synchronous Rectifier

#### Features

- 16 A, 30 V  $R_{DS(ON)} = 8.0 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$  $R_{DS(ON)} = 9.5 \text{ m}\Omega$  @  $V_{GS} = 4.5 \text{ V}$
- High performance trench technology for extremely low  $R_{\text{DS(ON)}}$
- No inductance between MOSFET and Schottky
- 40% reduction in Body Diode Forward Voltage
- Optimized to reduce losses in Synchronous Buck Regulators
- FLMP SO-8 package for enhanced thermal performance.





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
$V_{DSS}$	Drain-Source Voltage		30	V
V <sub>GSS</sub>	Gate-Source Voltage		±16	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	16	А
	– Pulsed		60	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	3.13	W
		(Note 1b)	1.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	°C/W

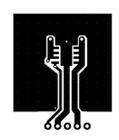
### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS7064SN3	FDS7064SN3	13"	12mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		I.		l .	I.
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		26		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μА
I <sub>GSS</sub>	Gate-Body Leakage	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	1.4	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C		-2		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V},  I_D = 16 \text{ A}$ $V_{GS} = 4.5 \text{ V},  I_D = 14 \text{ A}$ $V_{GS} = 10 \text{ V},  I_D = 16 \text{ A},  T_J = 125^{\circ}\text{C}$		6.5 7.5 9.1	8.0 9.5 11.5	mΩ
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_{D} = 16 \text{ A}$		70		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V,		2800		pF
Coss	Output Capacitance	f = 1.0 MHz		530		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			190		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.4		Ω
Switchin	g Characteristics (Note 2)			•		
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 15 \text{ V},  I_D = 1 \text{ A},$		11	20	ns
tr	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		20	22	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	7		50	80	ns
t <sub>f</sub>	Turn-Off Fall Time			18	33	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 16 \text{ A},$		25	35	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 5.0 V		6		nC
Q <sub>gd</sub>	Gate-Drain Charge	7		6		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings	•			•
Is	Maximum Continuous Drain-Source				4.3	Α
V <sub>SD</sub>	Drain–Source Schottky Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 4.3 A (Note 2)		0.4	0.7	V
t <sub>RR</sub>	Reverse Recovery Time	I <sub>F</sub> = 16 A		22		ns
Q <sub>RR</sub>	Reverse Recovery Charge	diF/dt = 300 A/us		20		nC

#### Notes

 R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a) 40°C/W when mounted on a 1in² pad of 2 oz copper

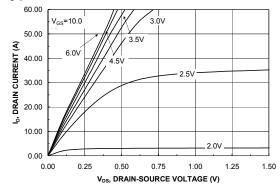


85°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

**2.** Pulse Test: Pulse Width <  $300\mu s$ , Duty Cycle < 2.0%

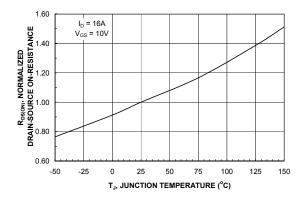
# **Typical Characteristics**



2.25 | V<sub>GS</sub> = 2.5V |

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



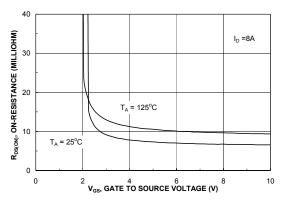
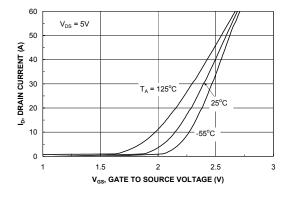


Figure 3. On-Resistance Variation withTemperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



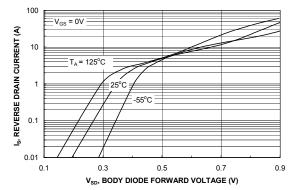
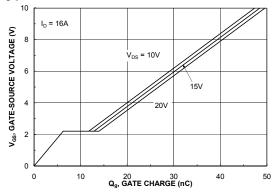


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



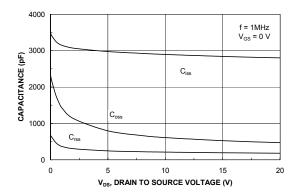
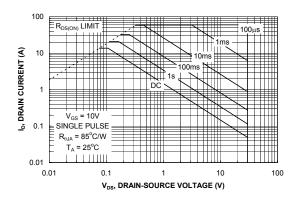


Figure 7. Gate Charge Characteristics.





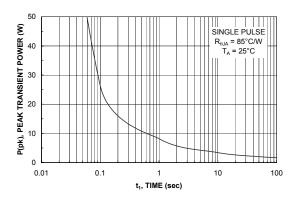


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

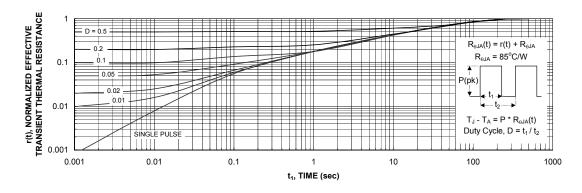


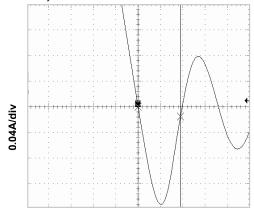
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

# Typical Characteristics (continued)

# **SyncFET Schottky Body Diode Characteristics**

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS7064SN3.



12.5 nS/div

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

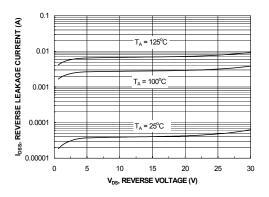
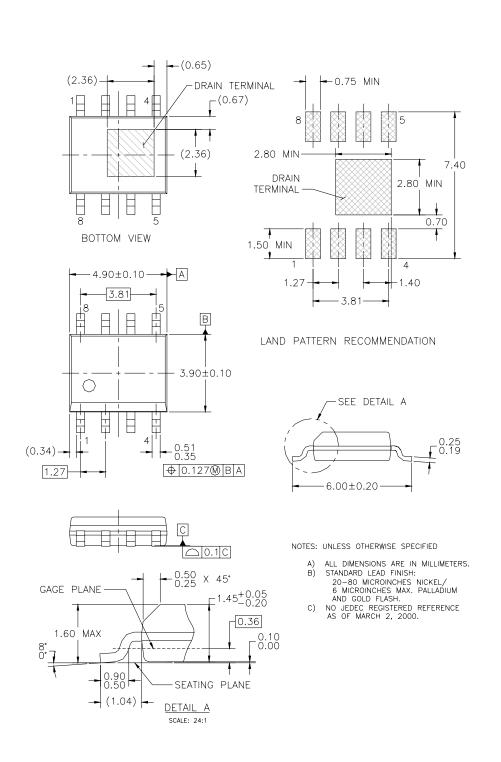


Figure 13. SyncFET body diode reverse leakage versus drain-source voltage and temperature

### **Dimensional Outline and Pad Layout**



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